



New Perspectives in Pest Management

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Message from the Guest Editors

Human population growth and climate change are presently some of the most discussed challenges, which are likely to affect the efficacy of protection technologies, and pest control measures such as host-plant resistance, natural enemies, biopesticides, and synthetic chemicals are likely to be affected by climate change. At the same time, from remote sensing technologies with advanced imaging to “omics” with powerful computational systems, diverse new technologies are available that provide powerful tools to drive innovation in pest management. These novel technologies call for multi-disciplinary research collaborations between geneticists, agronomists, ecologists, software programmers, engineers, and other specialists. This Special Issue of the journal Applied Science calls for original research articles and relevant state-of-the-art reviews and perspectives dealing with new perspectives in pest management.

Key words:

- pest management
- genetic engineering
- remote sensing
- omics
- biotechnology





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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